

SUPPORTING INFORMATION

№2

Preparation of a Microsized Cerium Chloride-Based Catalyst and its Application in Michael Addition of β -Diketones to Vinyl Ketones

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X-ray powder diffraction

Three powder patterns were measured for each sample – **B**, **C** and **D**, one pattern was measured immediately after the synthesis, and the next two patterns – after the incubation for 10 *min* and 50 *min*, respectively, in an open air. Since all patterns exhibited the same features, herewith we present the results observed for the sample **C** only.

The first X-ray powder diffraction pattern for the sample **C** (pattern *CI*) was measured immediately after the synthesis at Huber G670 Guinier camera (Cu $K\alpha_1$ radiation, $\lambda = 1.54059$ Å) equipped with an imaging-plate detector. To minimize the contacts with an atmosphere, the powder sample was placed between the two thin polymeric films penetrable for X-rays, and the measurements were performed during 5 *min*. All observed diffraction peaks belong to the known hexagonal crystal structure of $CeCl_3$.¹ The results of Rietveld refinement for the pattern *CI* are shown in Figure S1. In the refinement performed with the program *MRIA*,² the atomic coordinates were taken from the literature¹ and fixed, so variables were – background and peak shape parameters, and hexagonal unit cell dimensions *a* and *c* refined to the values 7.423(2) and 4.310(2) Å, respectively.

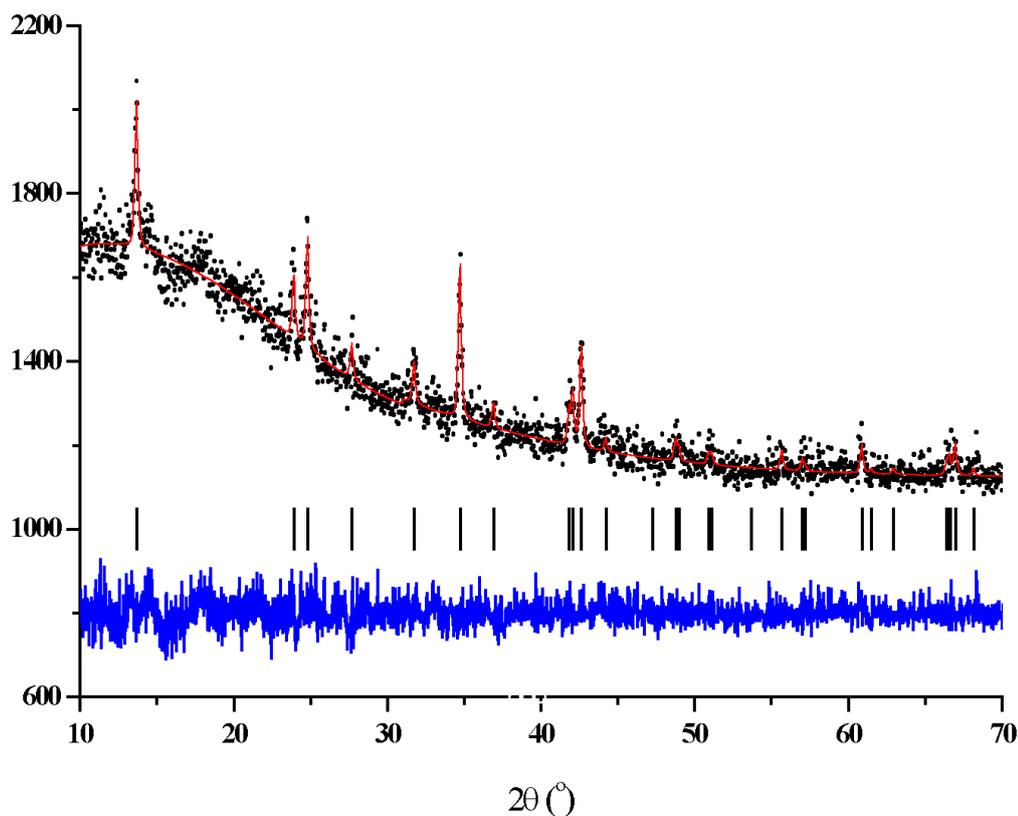


Figure S1. The Rietveld plot for the pattern *C1* showing the experimental (black dots), calculated (red) and difference (blue) curves. The vertical bars denote calculated positions of the diffraction peaks for phase CeCl_3 .

The second X-ray powder diffraction pattern for the sample **C** (pattern *C2*) was measured at Panalytical EMPYREAN instrument with a linear X'celerator detector using Ni-filtered $\text{Cu K}\alpha$ radiation. The 10 *min* measurements were started after incubation for 10 *min* in an open air. Most of the observed diffraction peaks belong to the known orthogonal crystal structure of $\text{CeCl}_3 \cdot 3\text{H}_2\text{O}$.³ The results of Rietveld refinement for the pattern *C2* are shown in Figure S2. In the refinement with the fixed atomic coordinates taken from the literature,³ the orthogonal unit cell dimensions *a*, *b* and *c* refined to the values 12.403(2), 8.816(2) and 6.933(2) Å, respectively. We attribute the weak peaks observed on a difference (blue) curve to the hydrates of CeCl_3 with the unknown crystal structures, i.e. monohydrate, dihydrate etc.

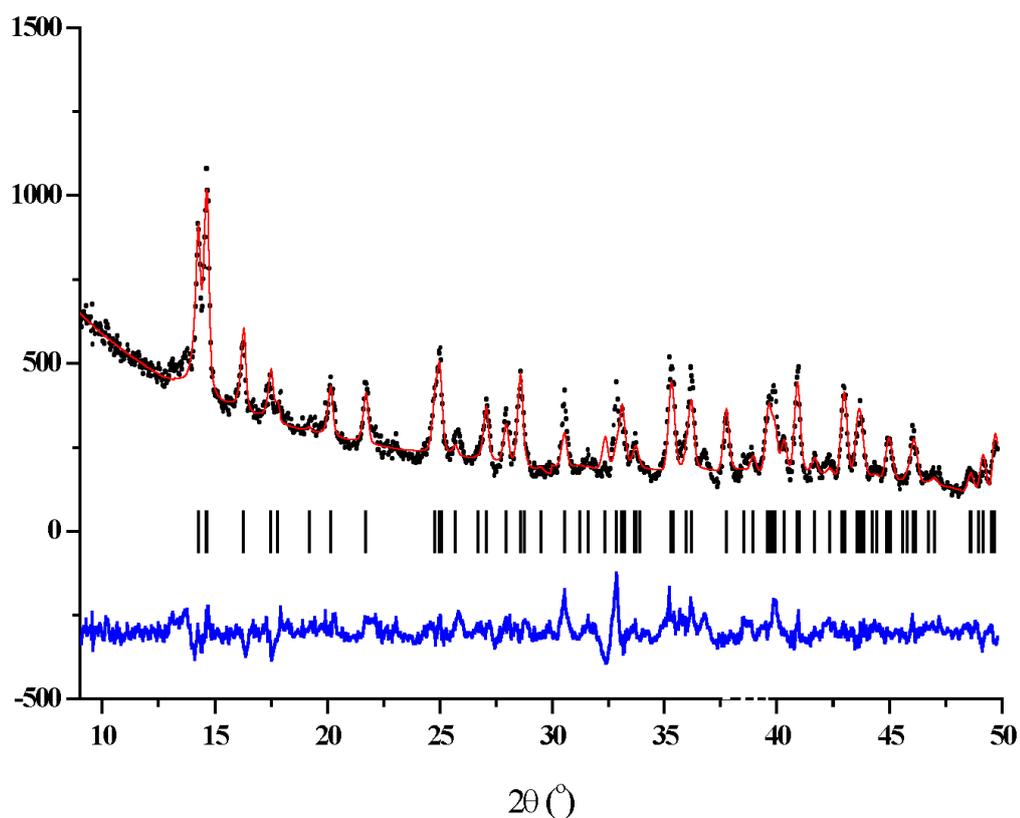


Figure S2. The Rietveld plot for the pattern C2 showing the experimental (black dots), calculated (red) and difference (blue) curves. The vertical bars denote calculated positions of the diffraction peaks for phase $\text{CeCl}_3 \cdot 3\text{H}_2\text{O}$.

The third X-ray powder diffraction pattern for the sample C (pattern C3) was measured at Panalytical EMPYREAN instrument. The 10 *min* measurements were started after incubation for 50 *min* in an open air. All observed diffraction peaks belong to the known triclinic crystal structure of $\text{CeCl}_3 \cdot 7\text{H}_2\text{O}$.⁴ The results of Rietveld refinement for the pattern C3 are shown in Figure S3. In the refinement with the fixed atomic coordinates taken from the literature,⁴ the triclinic unit cell parameters were refined to the following values - $a = 8.011(1) \text{ \AA}$, $b = 8.255(1) \text{ \AA}$, $c = 9.202(1) \text{ \AA}$, $\alpha = 71.48(2)^\circ$, $\beta = 72.44(2)^\circ$, $\gamma = 81.58(3)^\circ$.

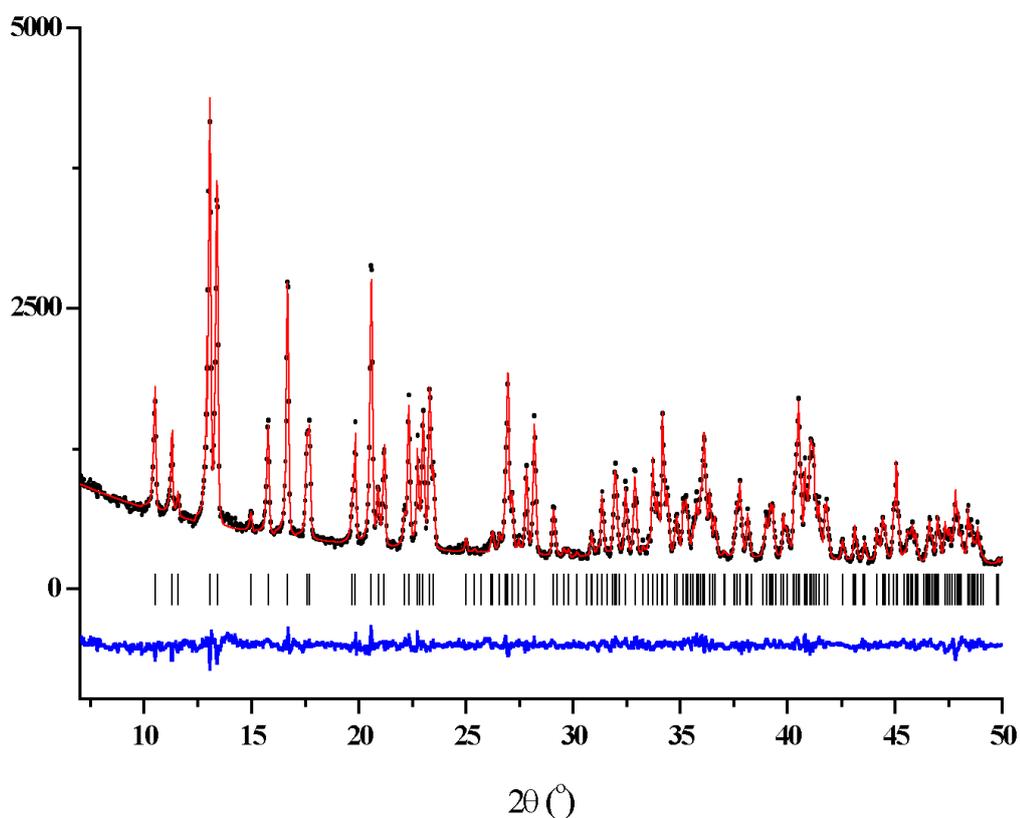


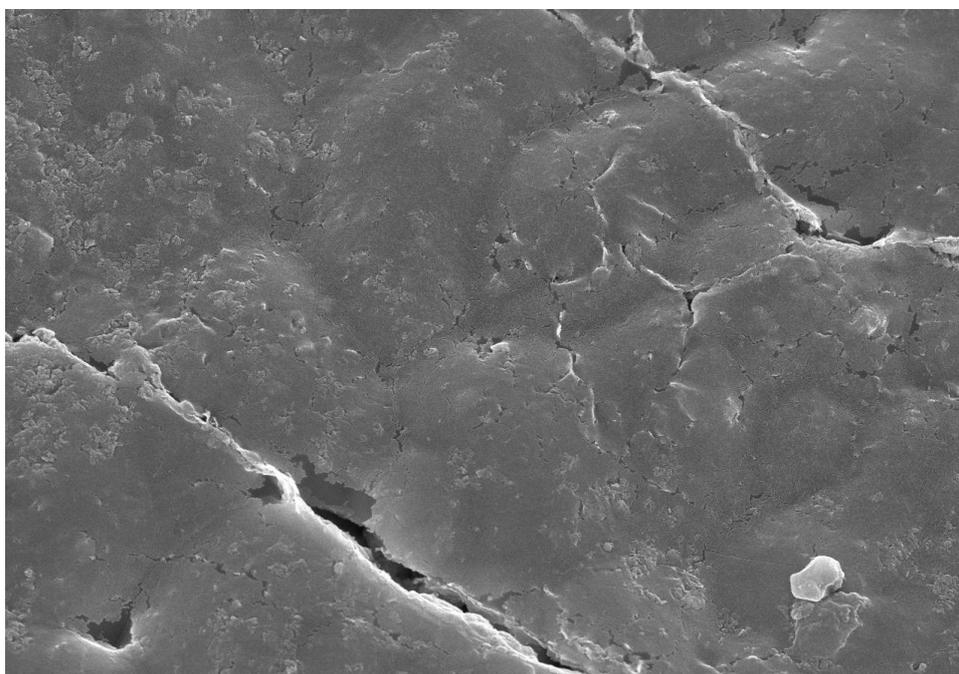
Figure S3. The Rietveld plot for the pattern *C3* showing the experimental (black dots), calculated (red) and difference (blue) curves. The vertical bars denote calculated positions of the diffraction peaks for phase $\text{CeCl}_3 \cdot 7\text{H}_2\text{O}$.

References.

- (1) Zachariasen, W.H. *Acta Crystallogr.* **1948**, *1*, 265-268.
- (2) Zlokazov, V. B.; Chernyshev, V. V. *J. Appl. Crystallogr.* **1992**, *25*, 447-451.
- (3) Reuter, G.; Fink, H.; Seifert, H.J. *Z. Anorg. Allgem. Chemie*, **1994**, *620*, 665-671.
- (4) Levason, W.; Webster, M. *Acta Crystallogr., Section E*, **2002**, *E58*, i76-i78.

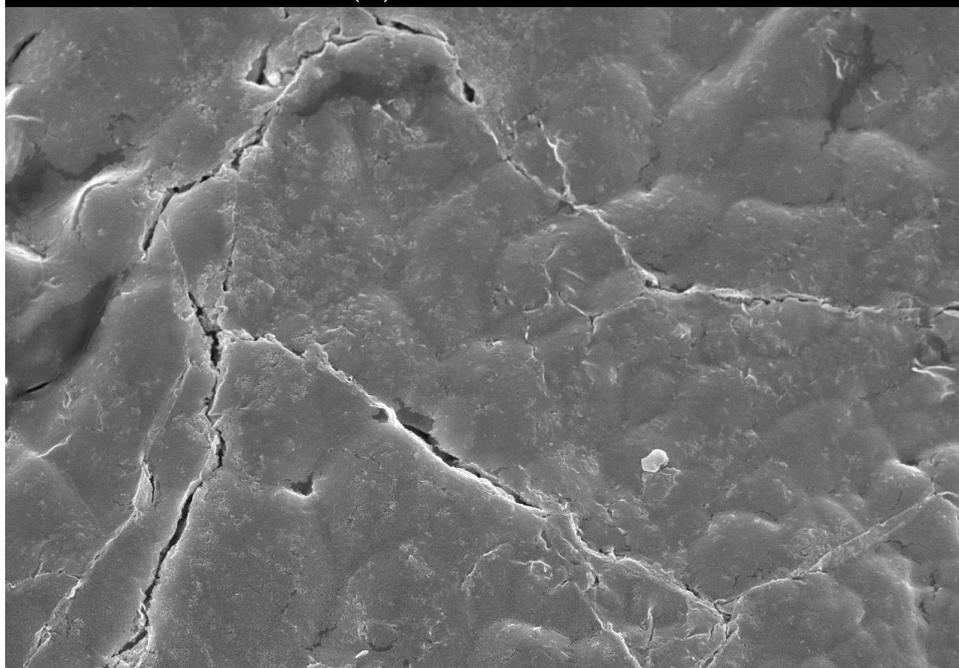
Micrographs of catalysts A, C, D, F

Catalyst A



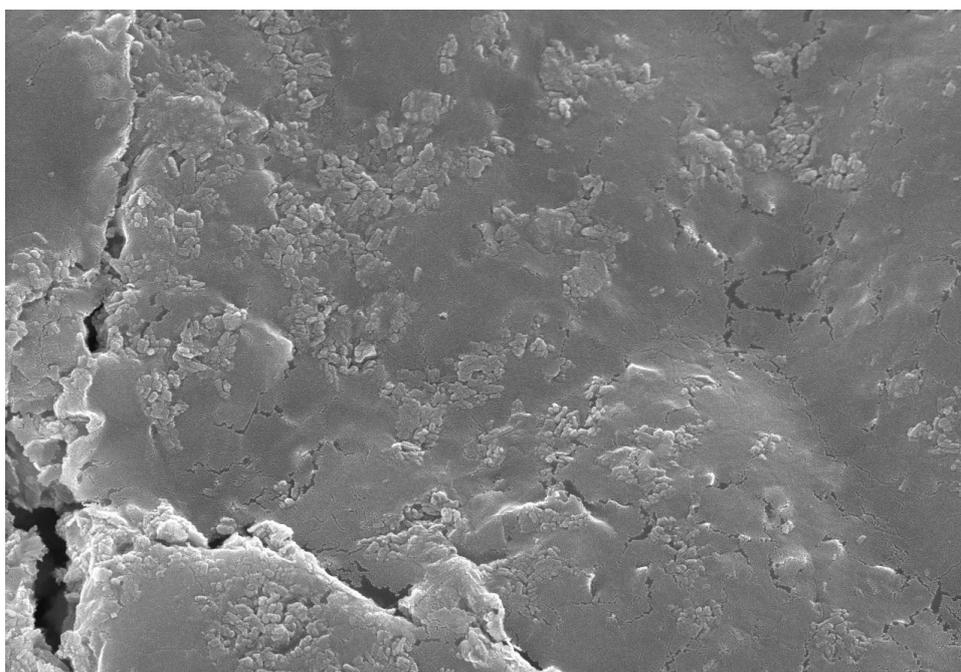
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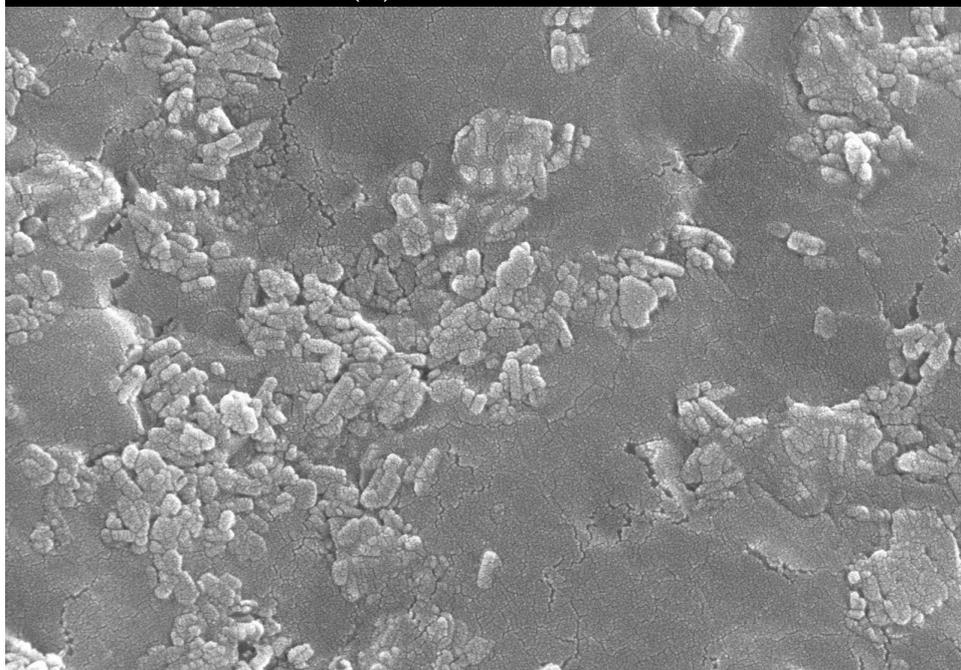
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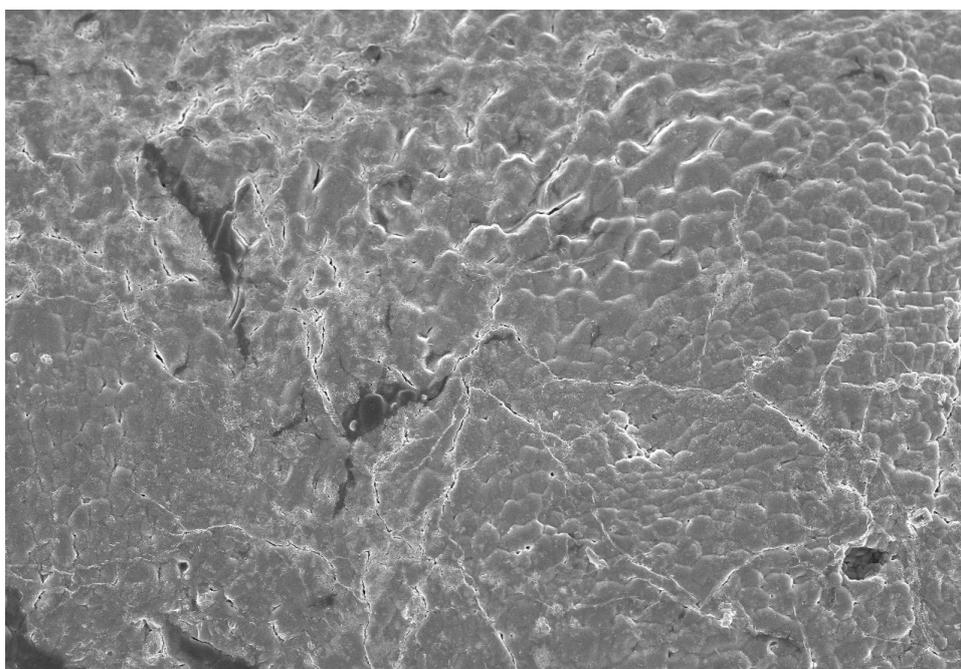
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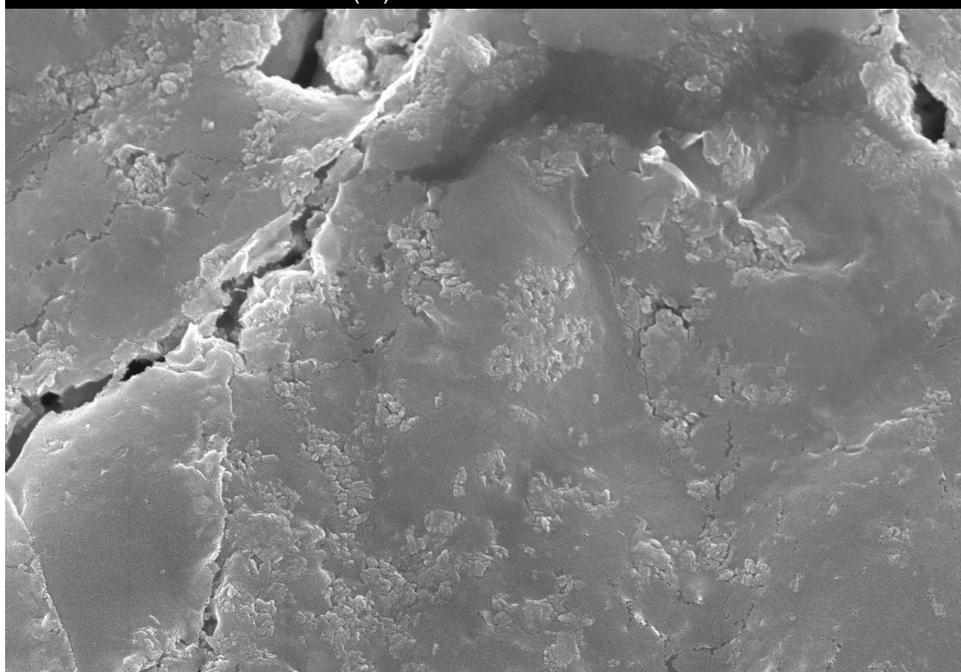
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1.00um



SU8000 10.0kV x1.00k SE(U)

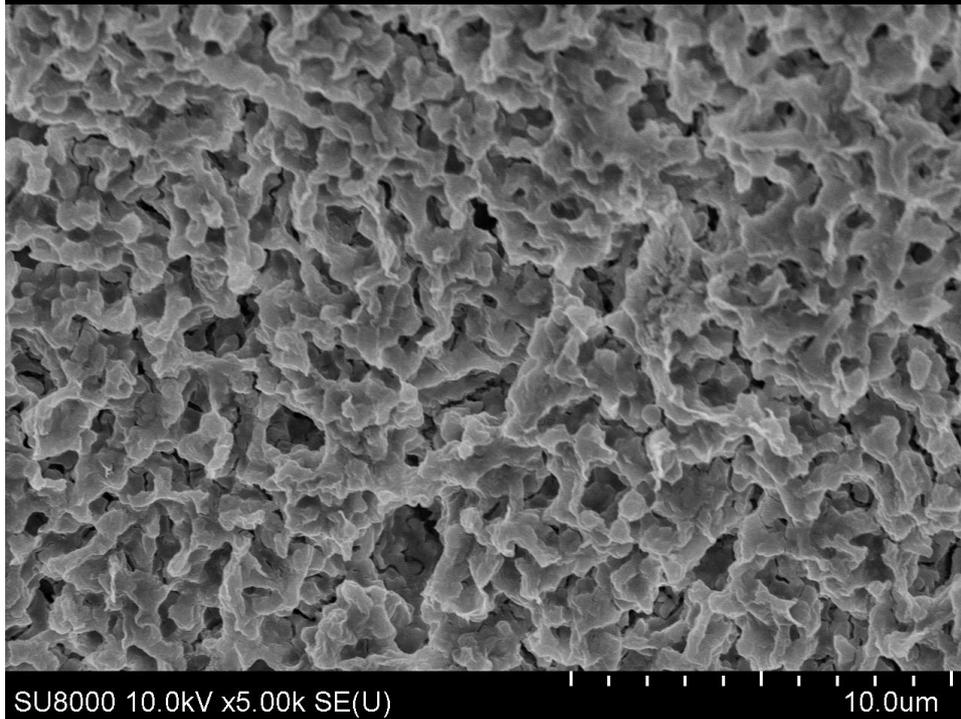
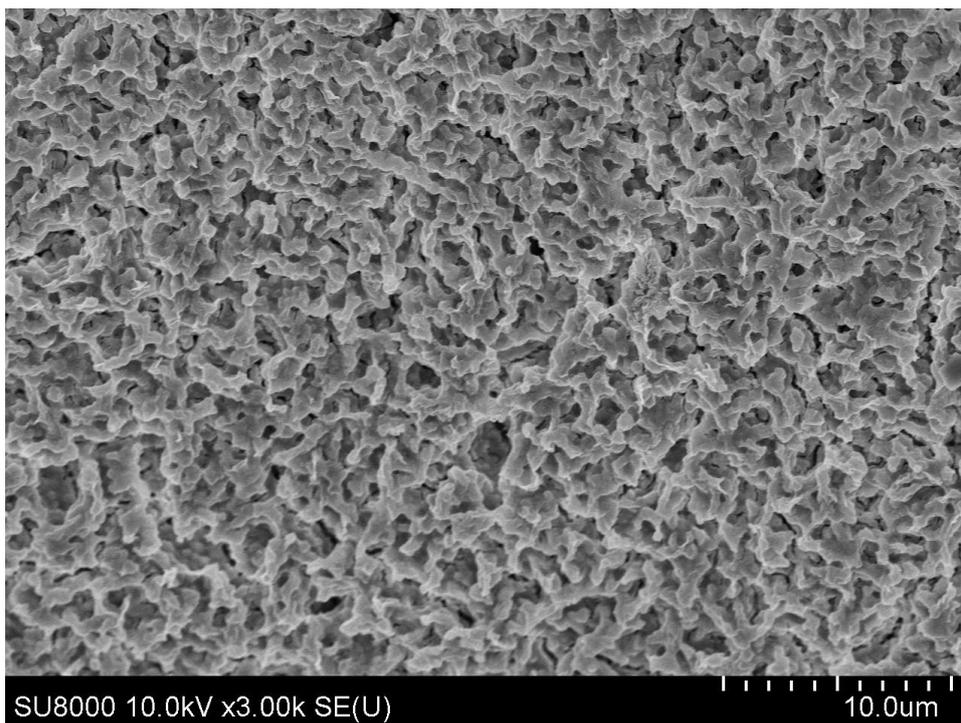
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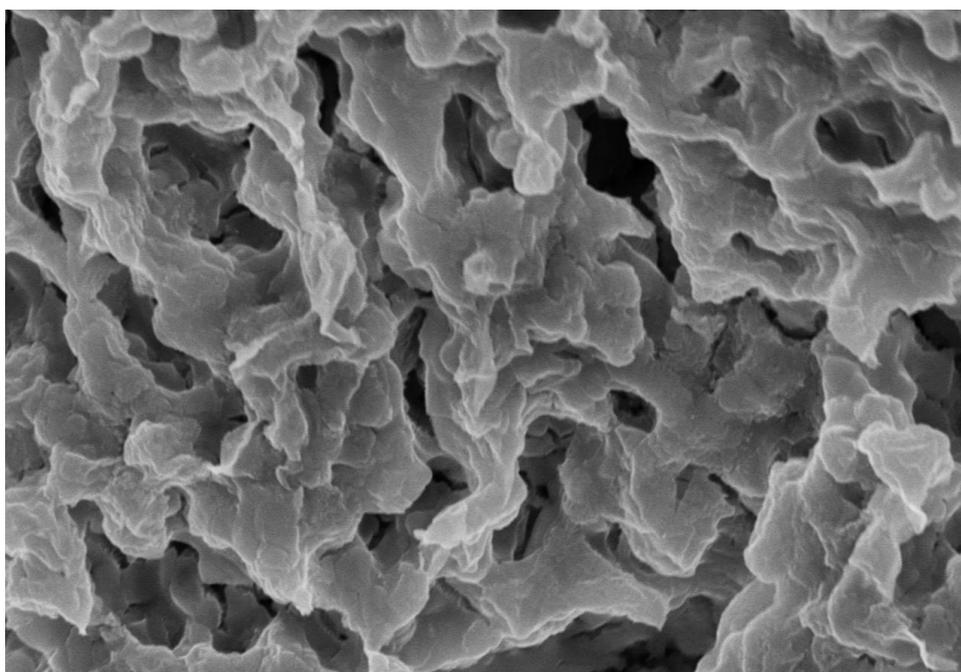


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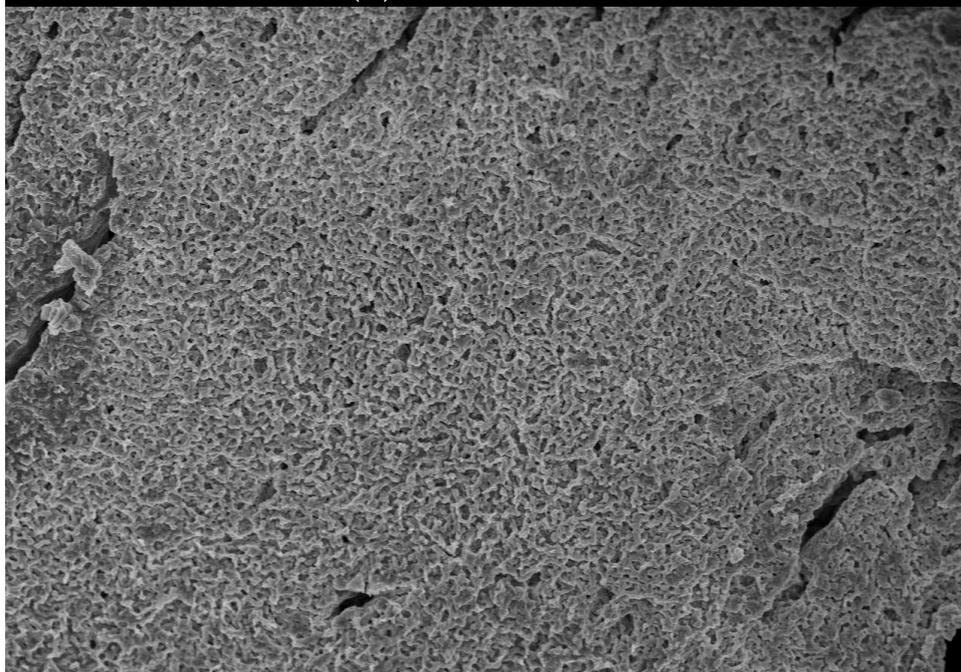
Catalyst C





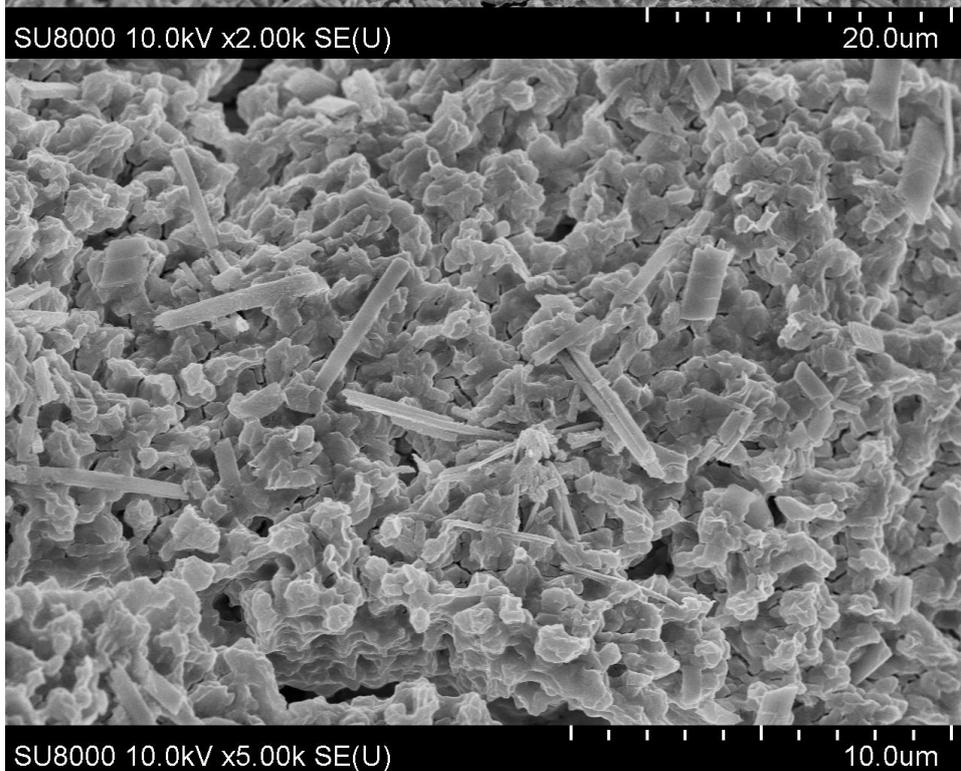
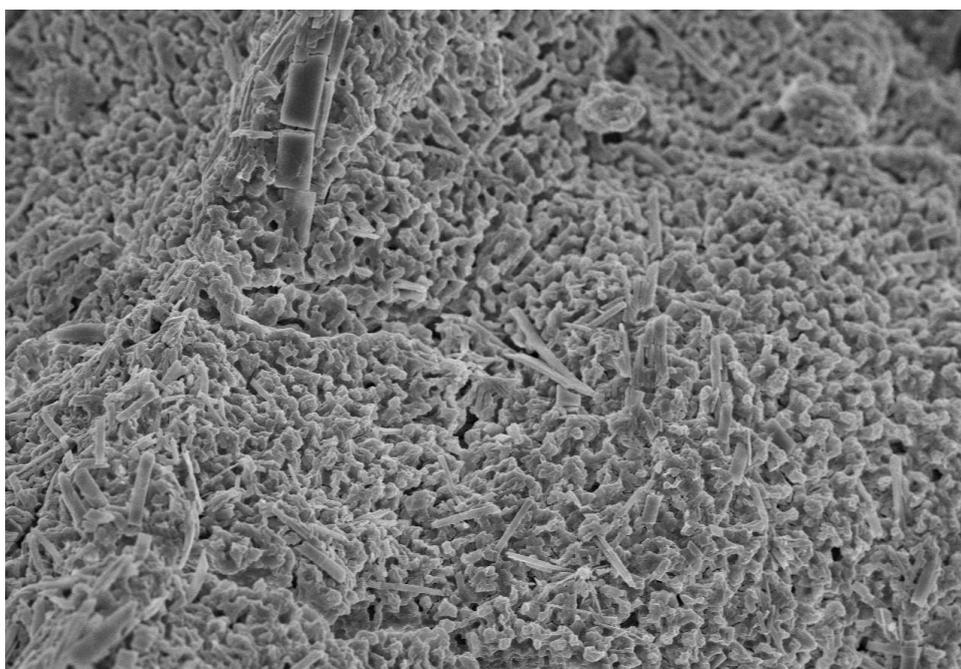
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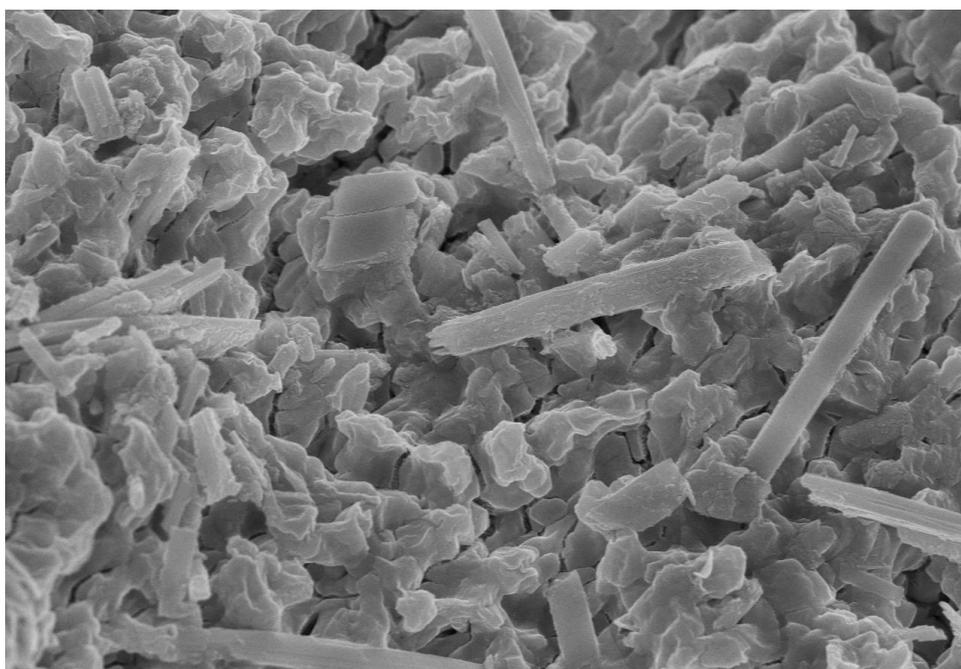
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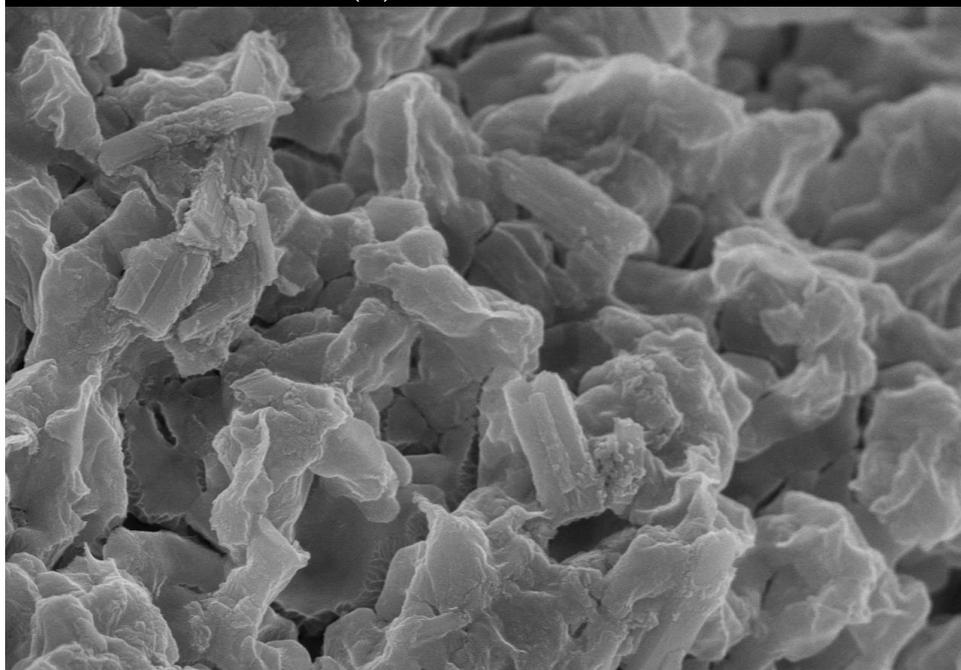
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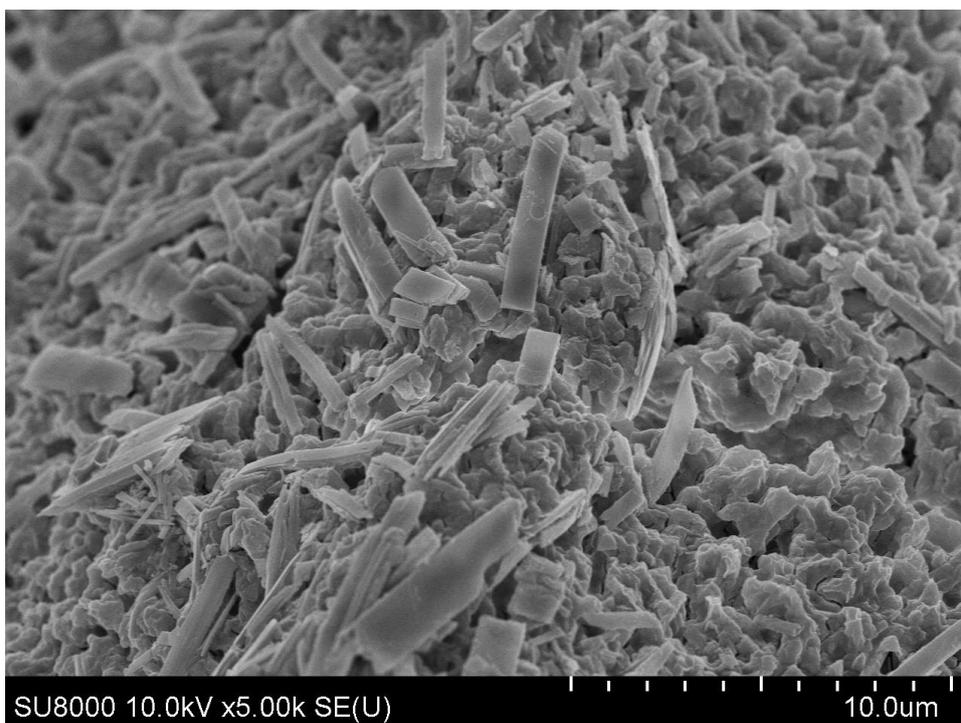
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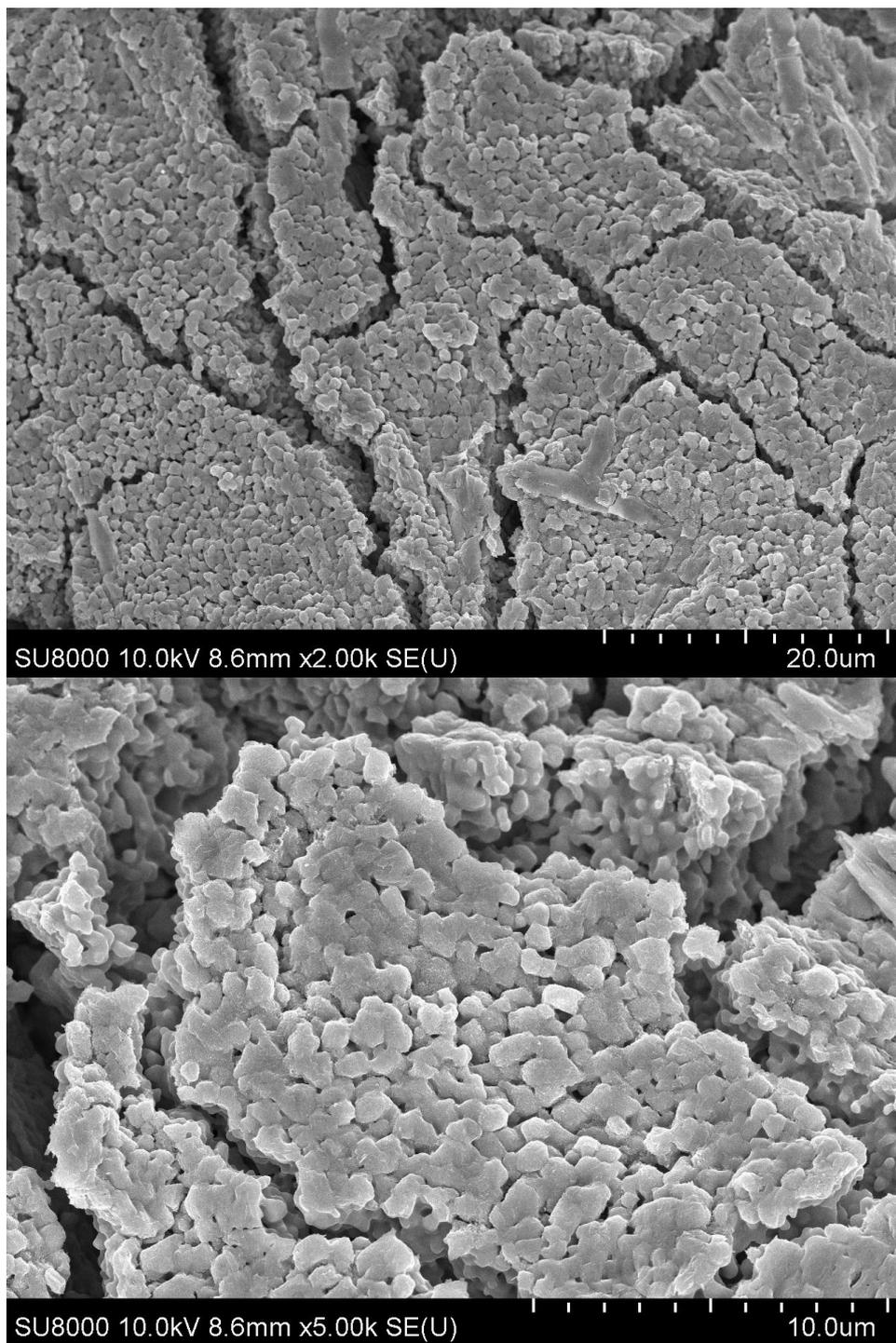


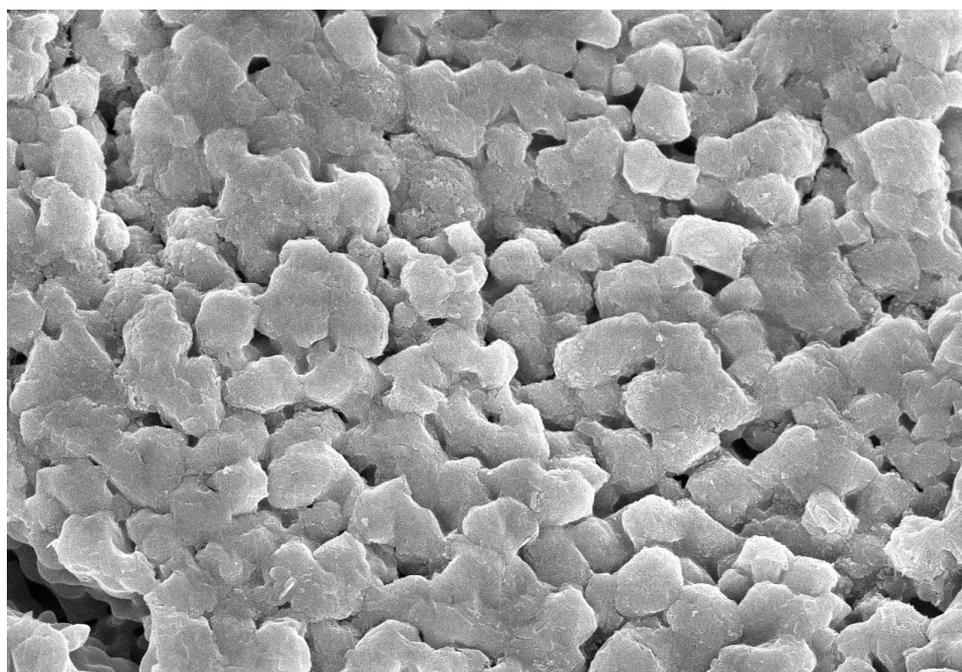
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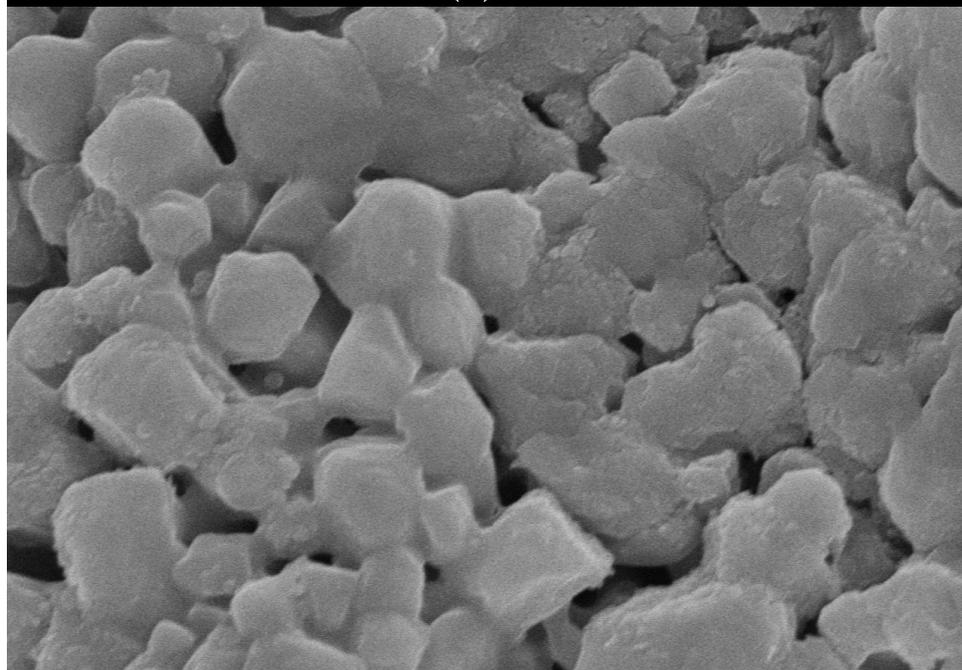
Catalyst D





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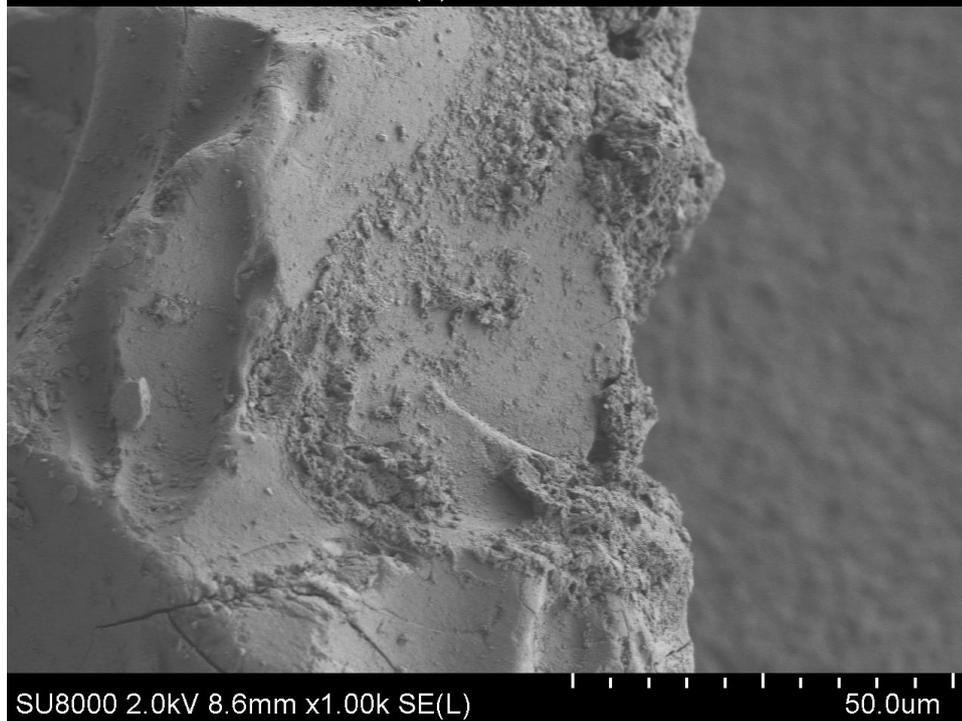
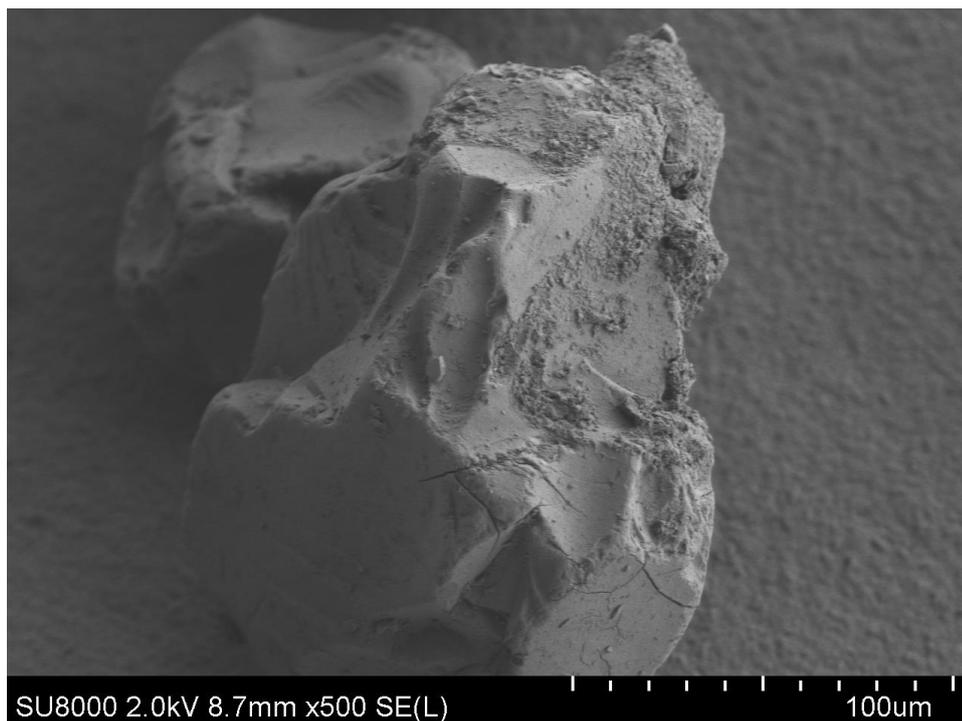
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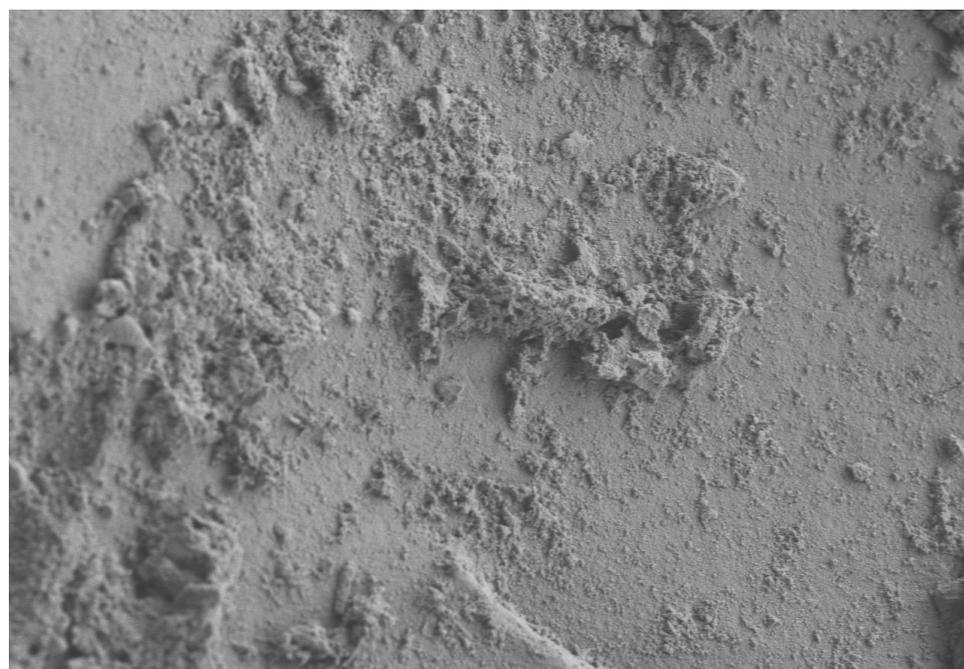


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Catalyst F





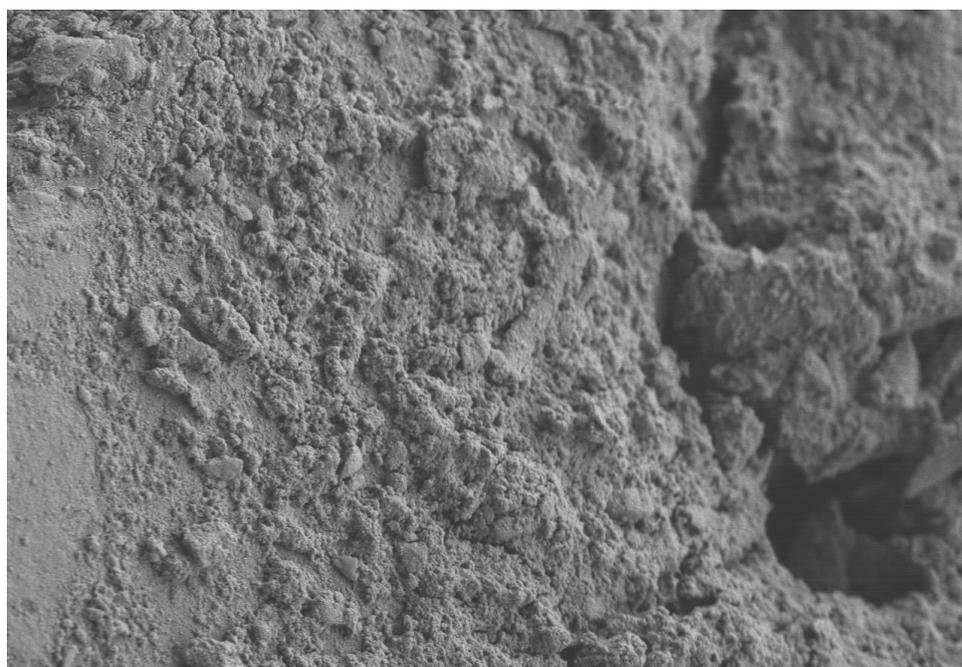
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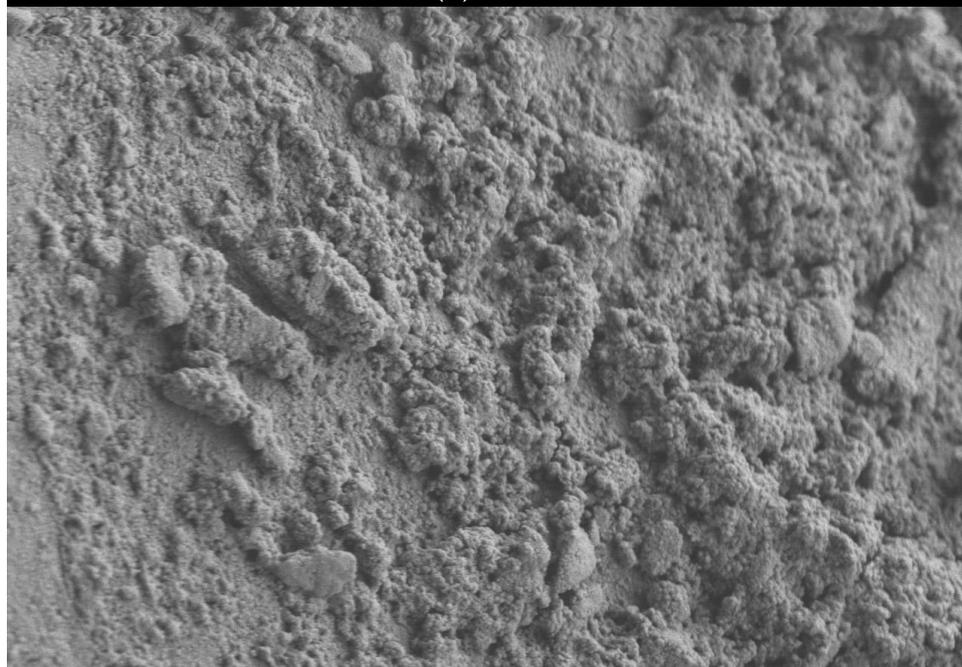
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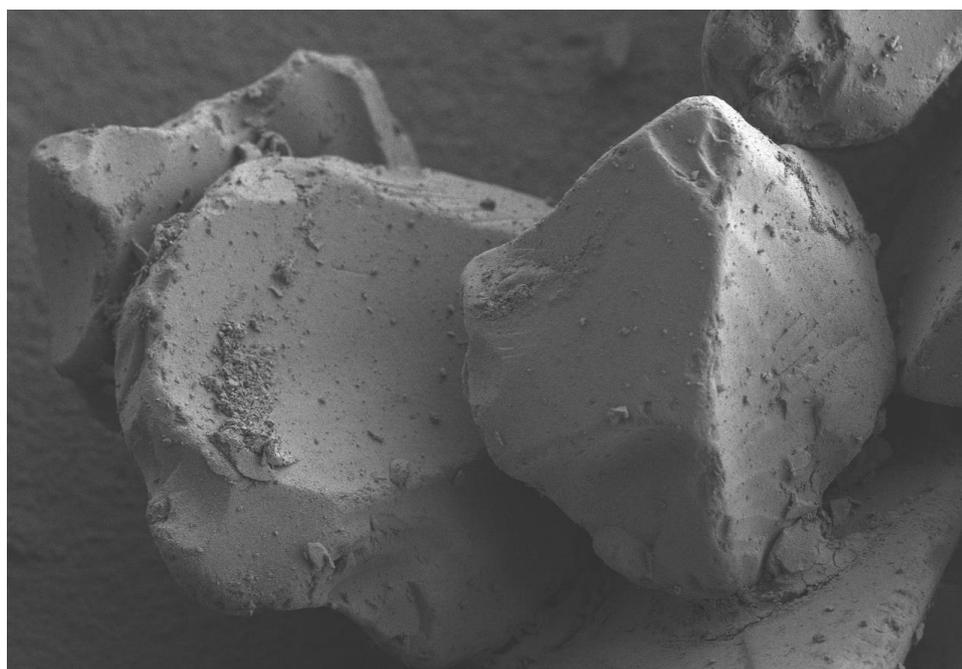
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10.0um



SU8000 2.0kV 8.6mm x10.0k SE(L)

5.00um



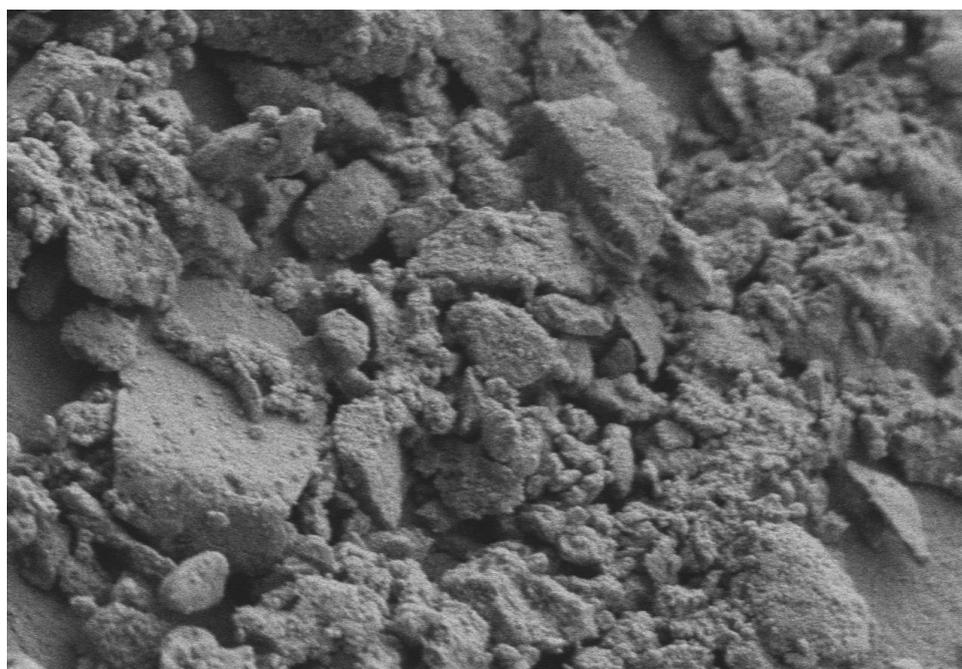
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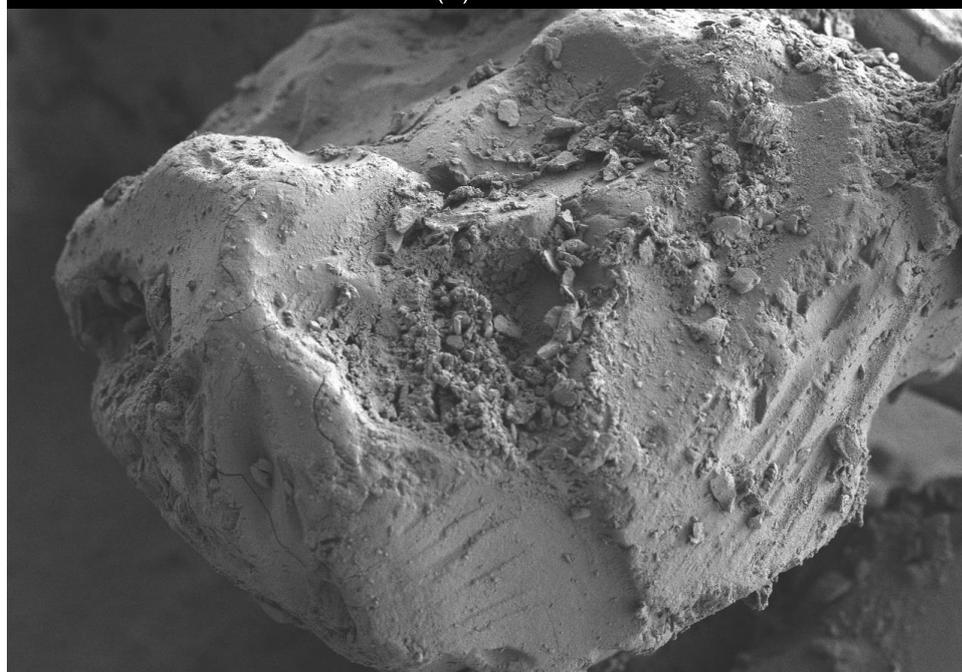
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10.0um



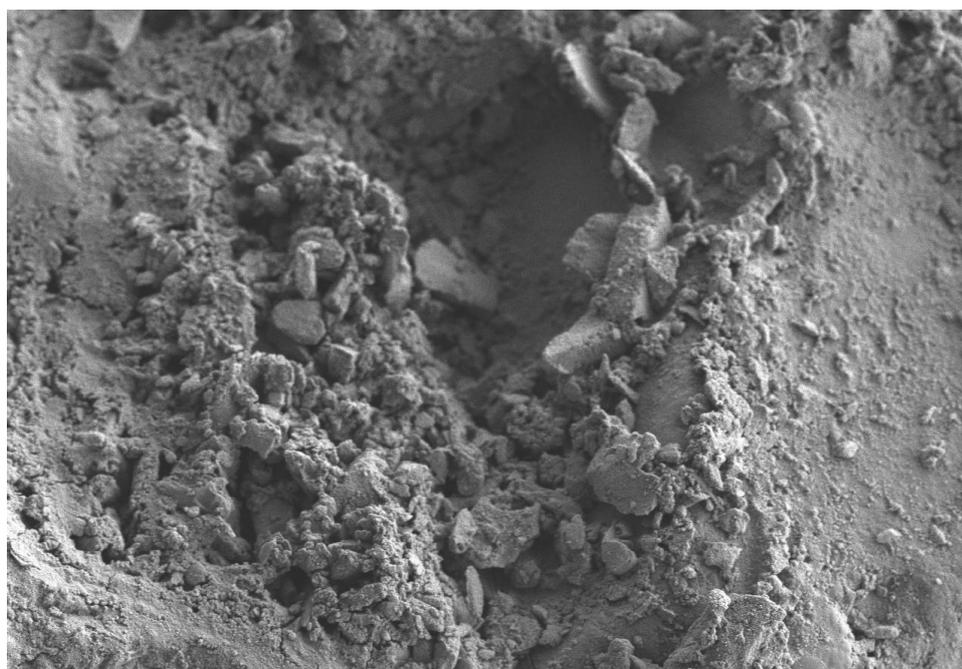
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5.00um



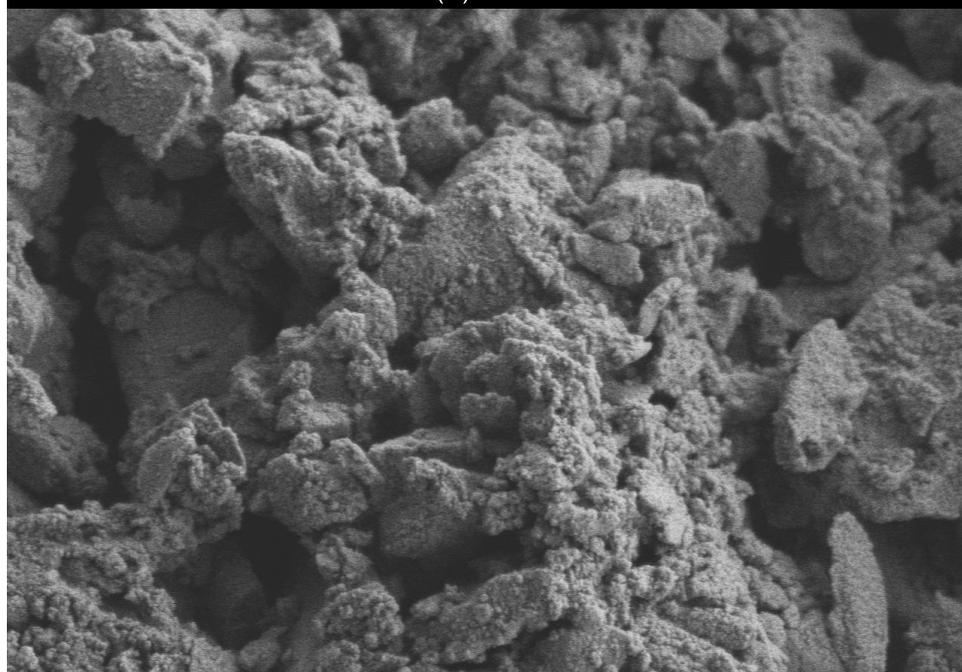
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50.0um



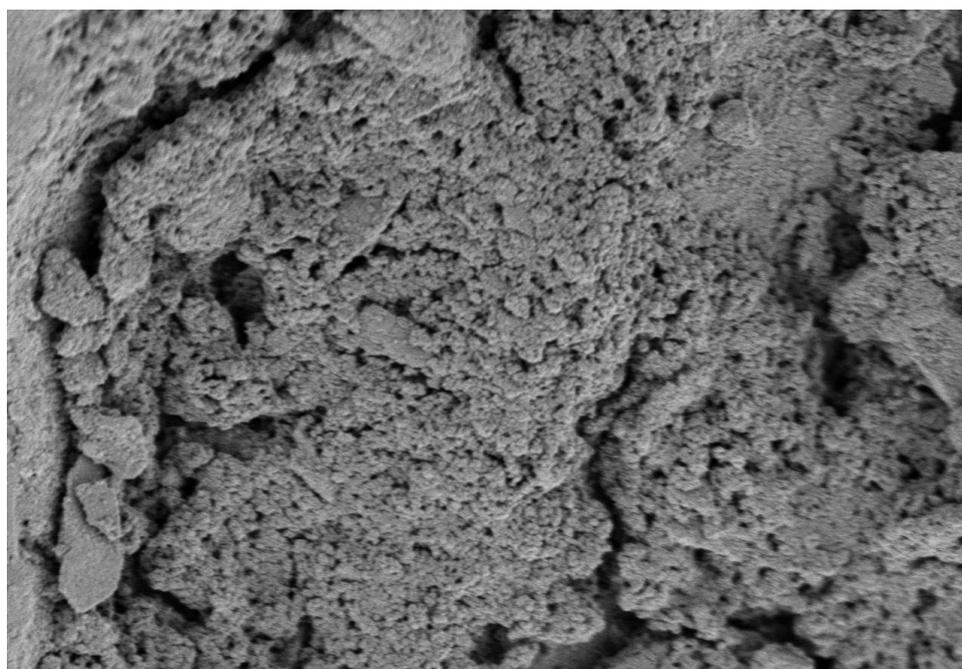
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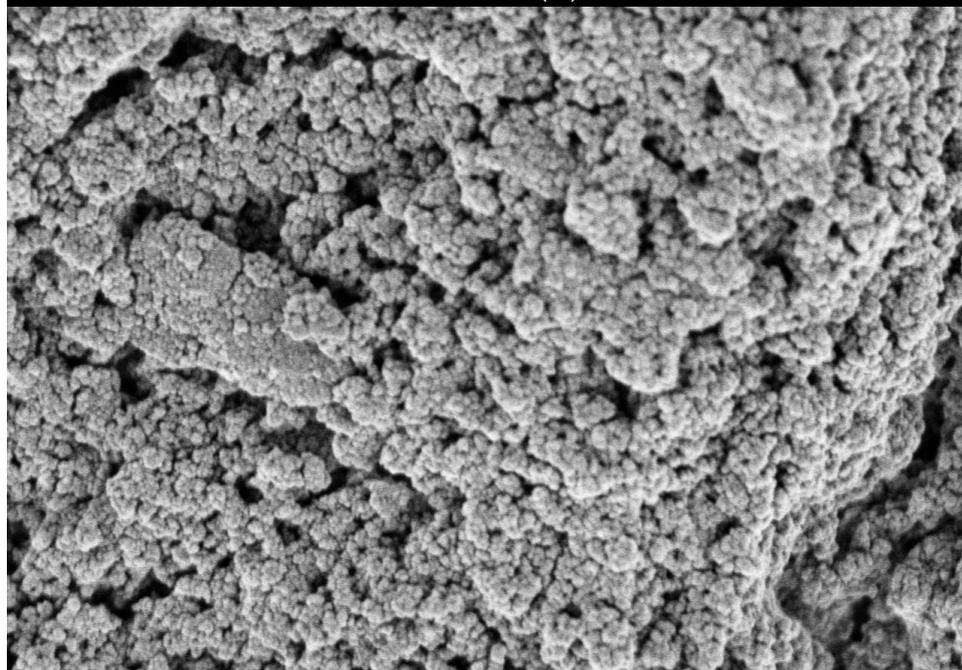


SU8000 2.0kV 8.6mm x10.0k SE(L)

5.00um



SU8000 1.0kV-D 4.5mm x10.0k SE+BSE(U) 5.00um



SU8000 1.0kV-D 4.5mm x30.0k SE+BSE(U) 1.00um